

Andreev tunneling in NIS junctions and and SINIS turnstiles



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NEC

1. Introduction

- Aim: Create a current standard with relative accuracy of 10⁻⁷ with SINIS turnstiles
- Higher order tunneling processes ultimately limit the charge quantization.
- Here we focus on Andreev reflection, the dominant

3. Counting single Andreev tunneling events

• SET electrometry is used to detect individual tunneling events between two metallic islands connected with an NIS junction:

4. Andreev tunneling in SINIS

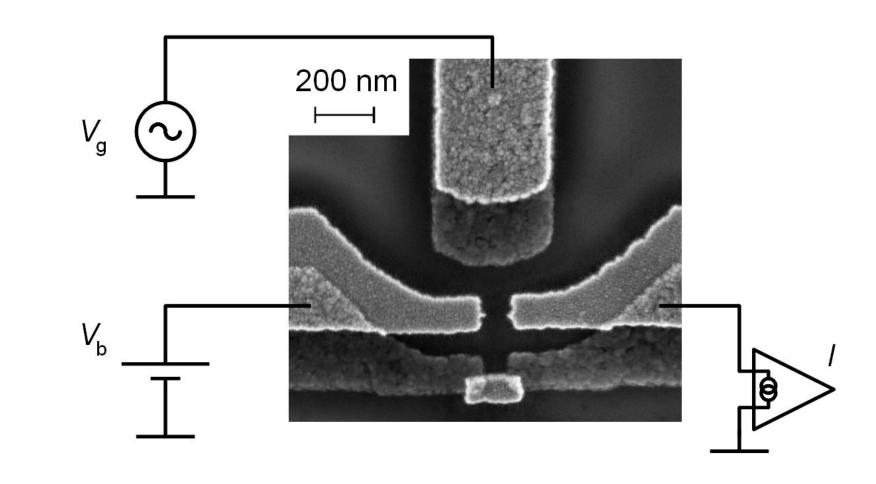
turnstiles

• Colored regions: measured current • Solid black lines: Andreev tunneling taken into account • Dotted blue lines: only single electron tunneling

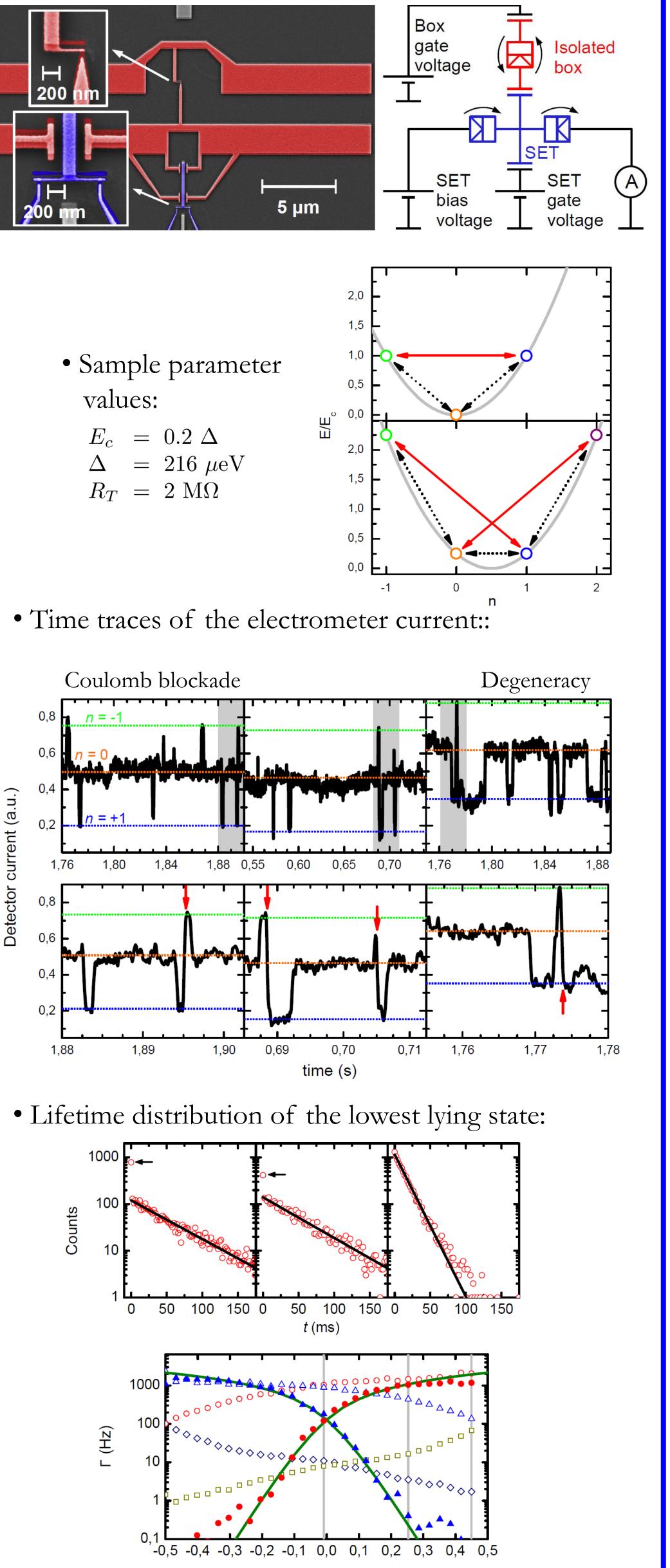
two electron process between a superconductor and a normal metal.

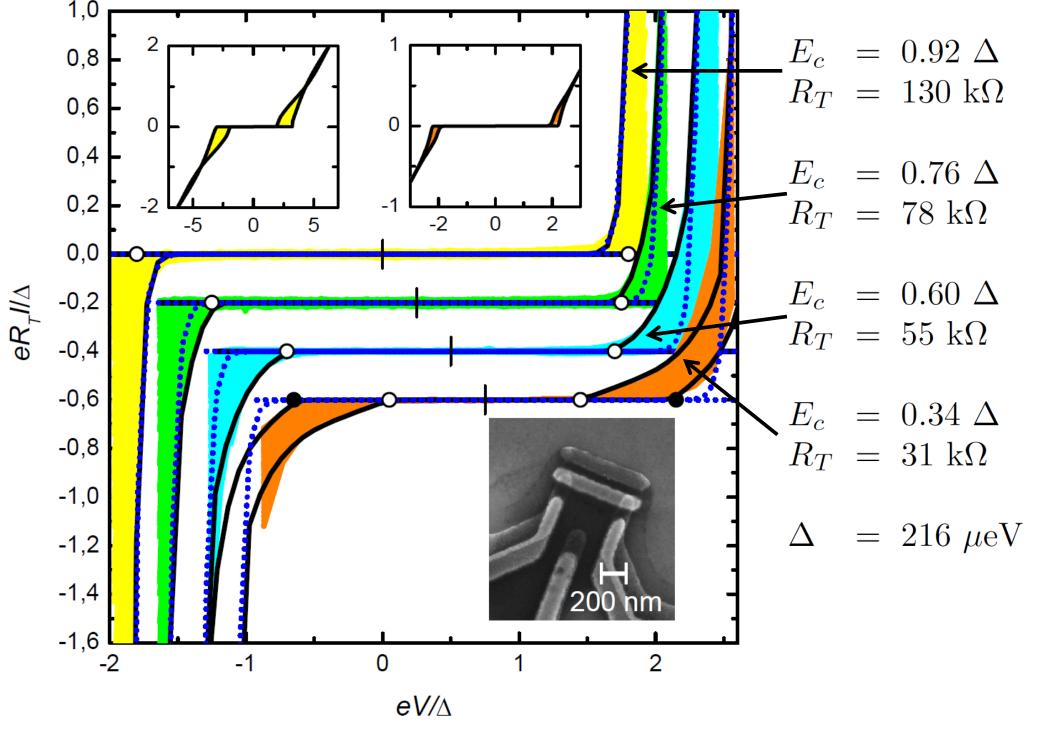
2. Basics

• Single electron transistor with superconducting leads and normal metallic island: (SINIS = SET with NIS junctions)

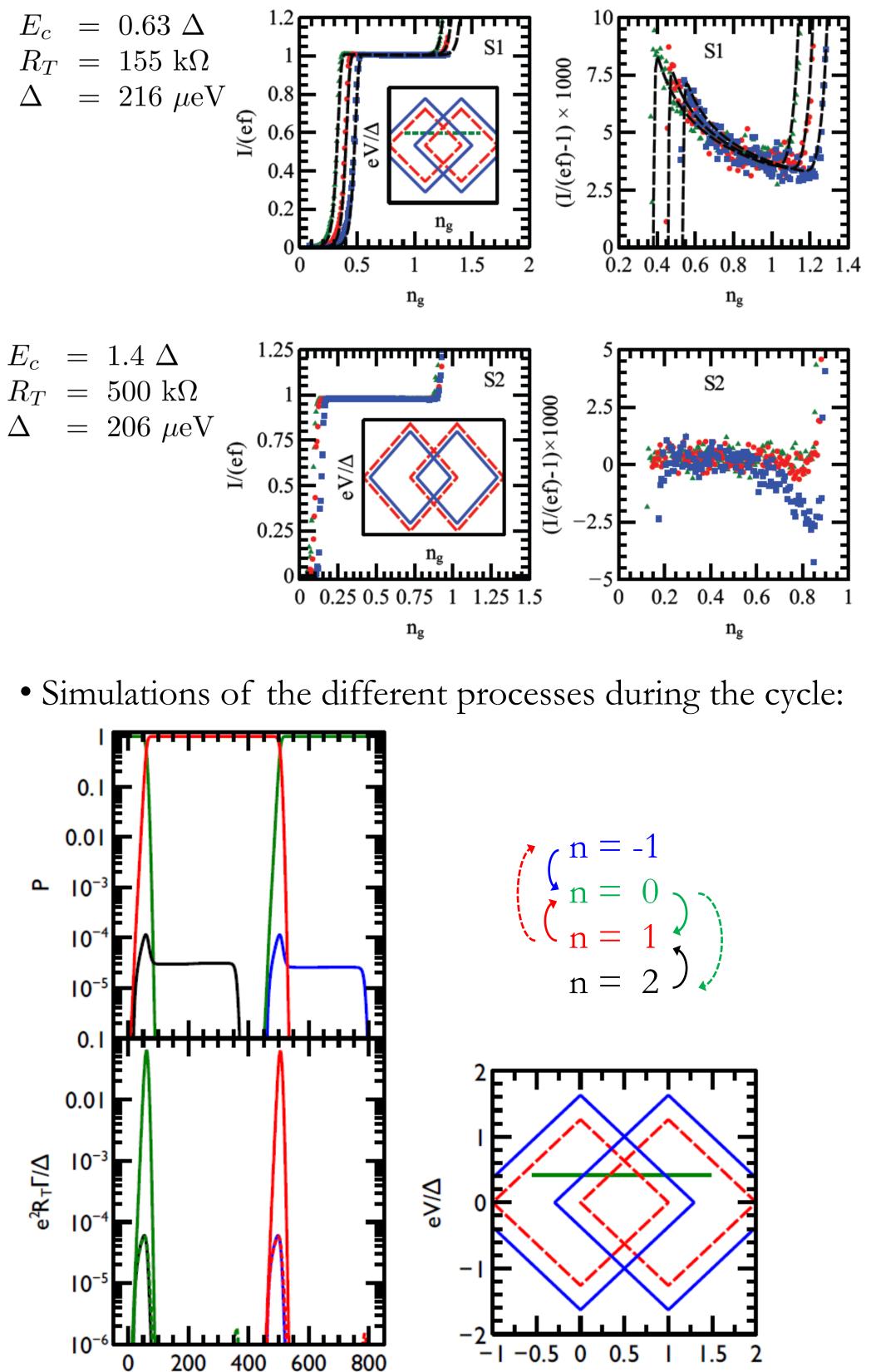


• DC current - voltage characteristics with extended stability regions for the charge states:

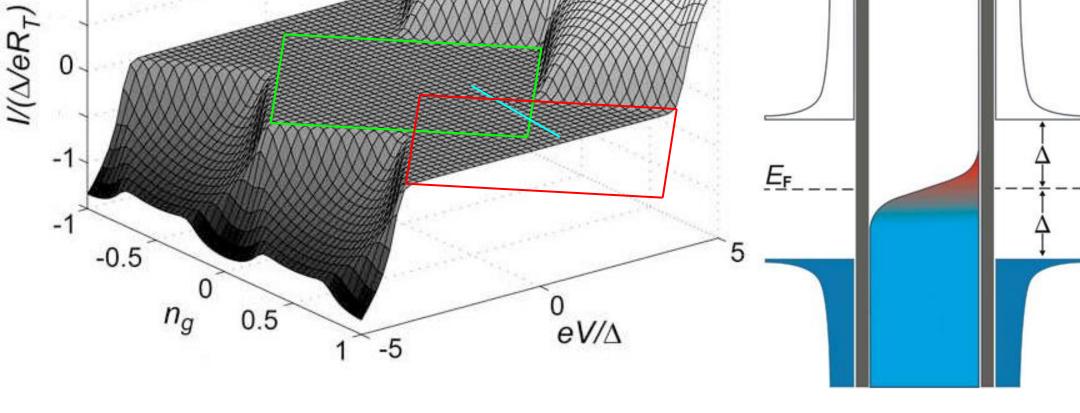




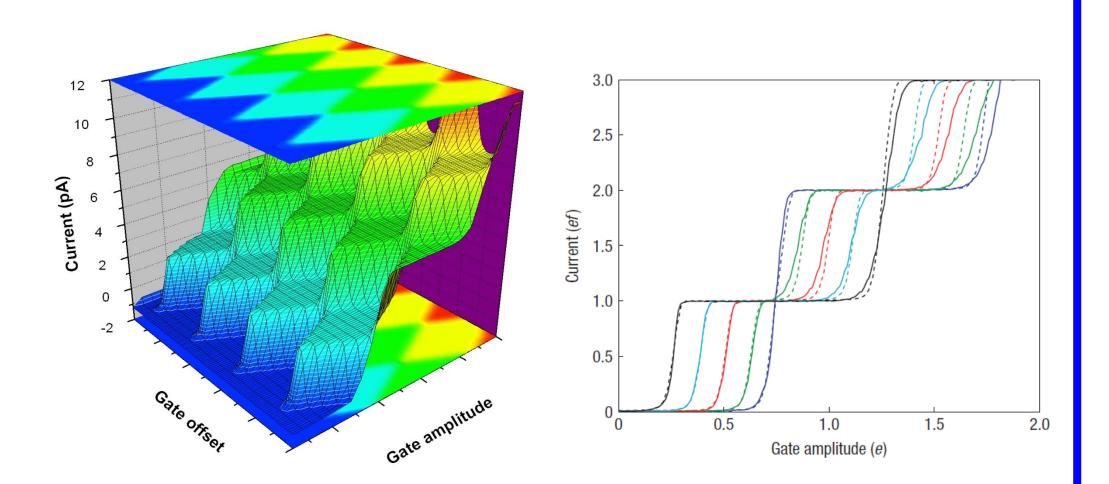
• Presence of Andreev tunneling during electron pumping: f = 10 MHz



n_g



• Charge pumping: DC voltage bias and a RF gate drive produces electron pumping with current I = nef







Maisi et al. arXiv:1012.5750 (2010)

Effective size of a conduction channel:

n_g

